

Spin polarization measurements of InAs based LED's

C.J. Meining, K.A. Korolev and B.D. McCombe

Department of Physics and CAPEM, University at Buffalo, SUNY, Buffalo, NY 14260, USA

P. Grabs, I. Chado, G. Schmidt and L.W. Molenkamp

Physikalisches Institut (EP3), Universität Würzburg, 97074 Würzburg, Germany

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SpinS

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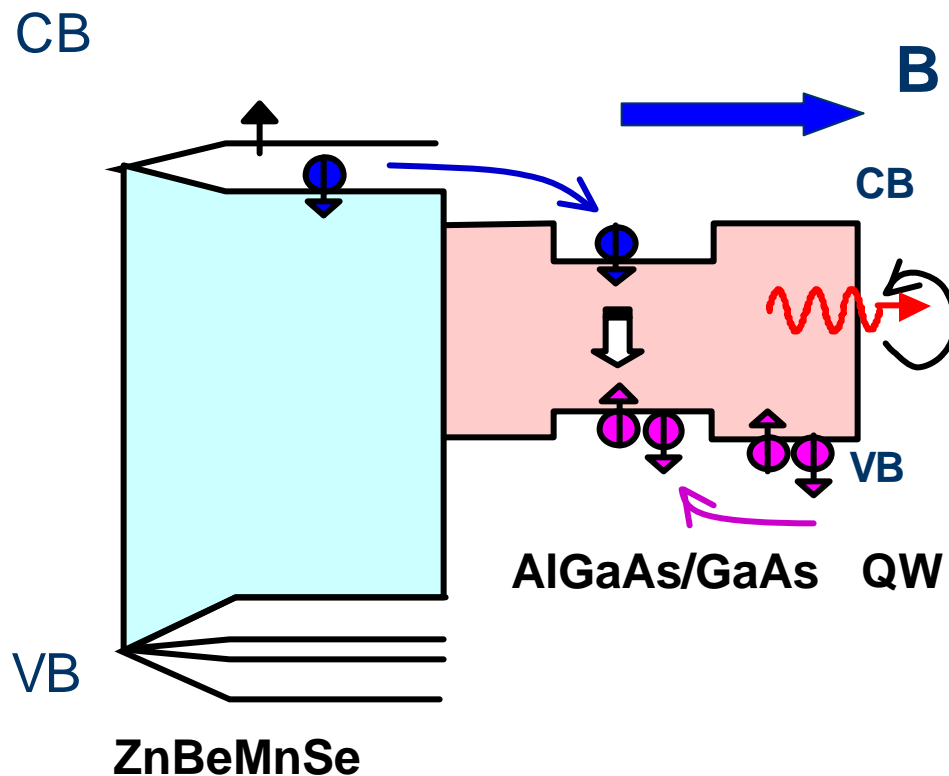
And by the

Center for Advanced Photonic and Electronic Materials

Outline:

- Motivation/Samples
- Experiment
- Results
- Discussion

Würzburg Group, Nature **402**, 787 (1999) and NRL/UB PRB (2000)

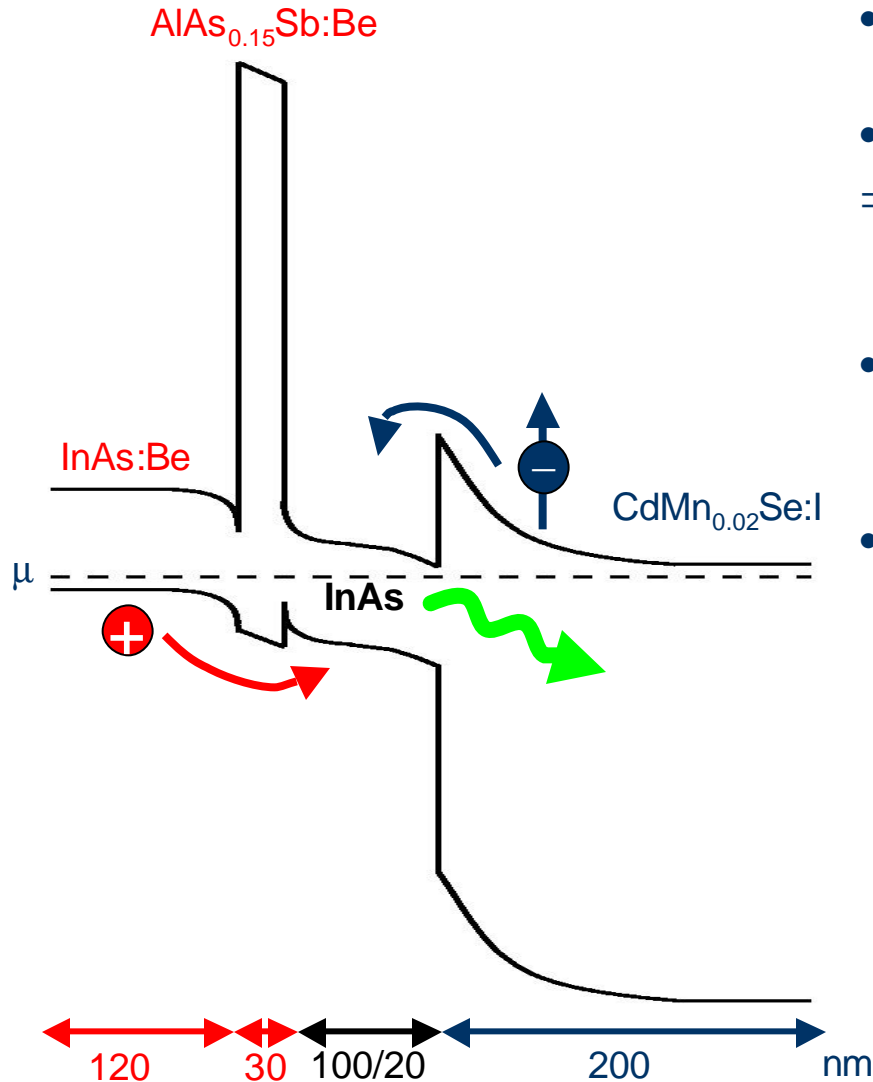


- Spin-injection into GaAs QW's by studying circular polarization of recombination
- Unique band alignment of NGS \Rightarrow Novel device structures (Spinphotonics)

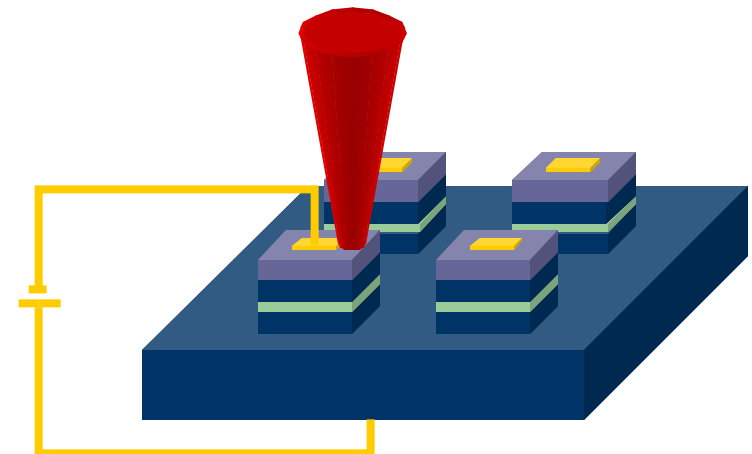


Investigate spin-injection efficiency by means of optical polarization degree of photoluminescence

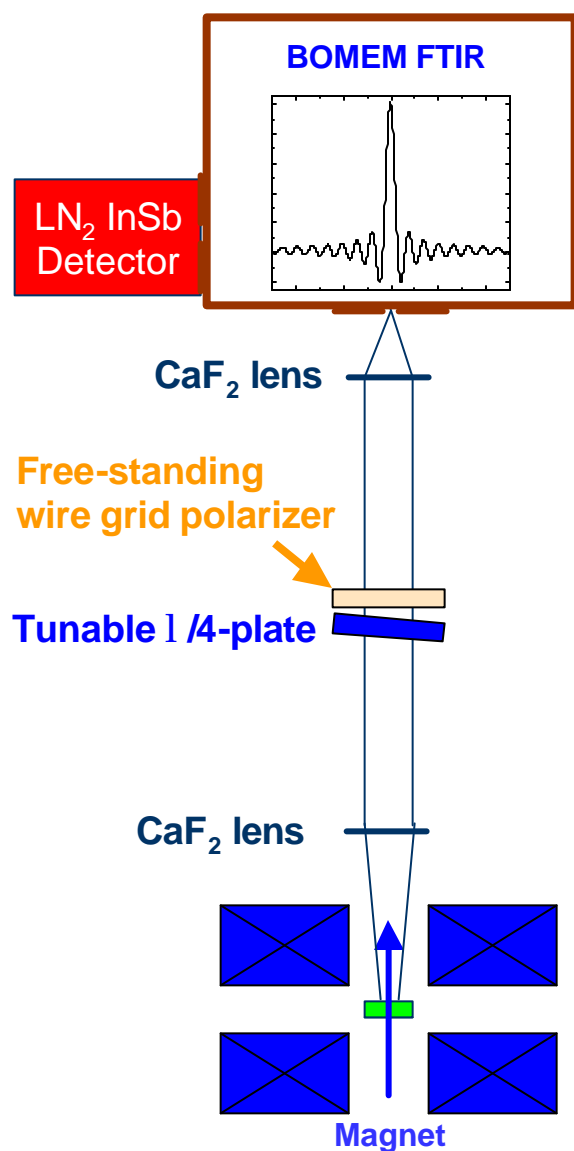
BUT: III-V NGS have large Zeeman splittings and enhanced non-parabolicity effects \Rightarrow Is spin-injection into NGS InAs measurable?



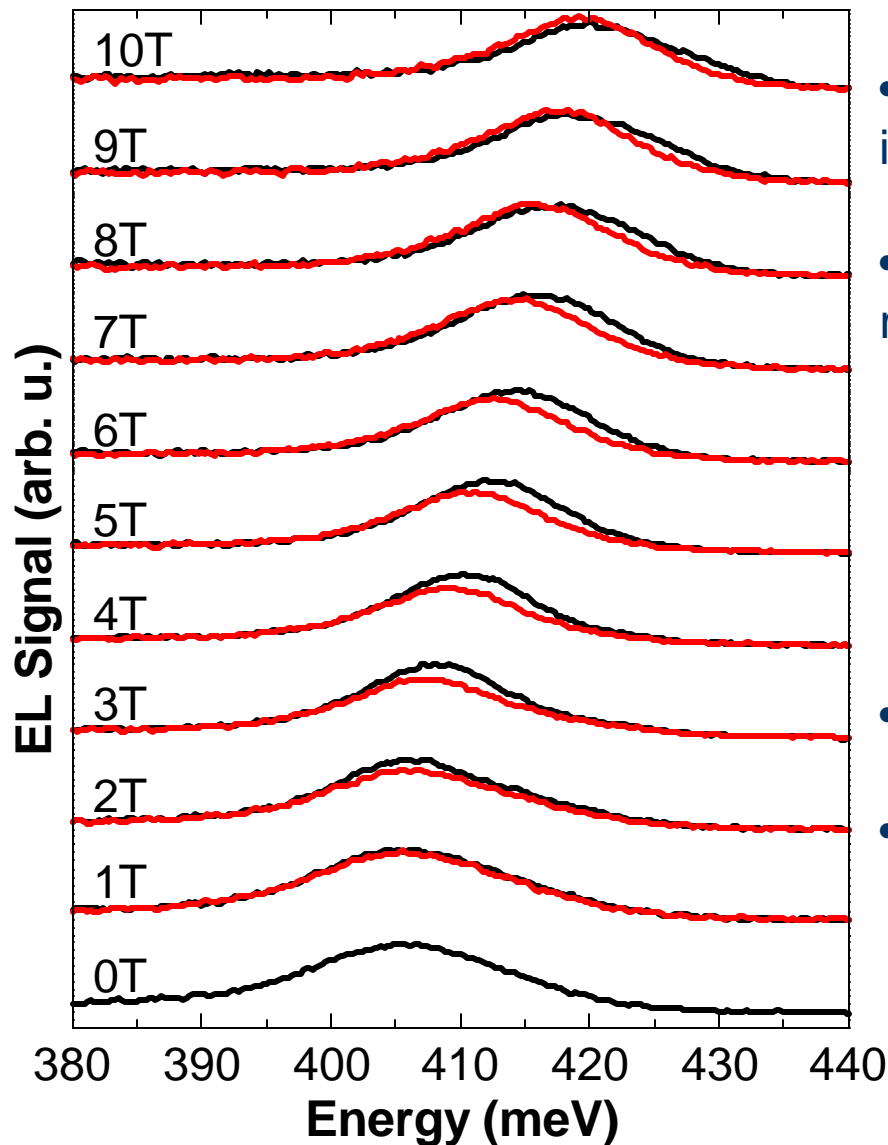
- Hybrid III-V/II-V p-i-n LED's
- asymmetric QW
⇒ high barriers for electrons ($\sim 1.8\text{eV}$) and holes ($\sim 0.86\text{eV}$)
- magnetic and nonmagnetic reference structures ($\text{CdMnSe:I} \leftrightarrow \text{CdSe:I}$)
- processed into (200 – 500) μm mesas with Au contacts



Experimental Setup



- 10T superconducting split coil magnet with sample immersed in liquid Helium
- CaF₂ lenses for collimation and focusing of EL
- Freestanding wire grids as linear polarizers
- Savart plate as tunable $\lambda/4$ -plate
 \Rightarrow wavelength of $\pi/2$ shift depends on angle of incident light
- Fourier Transform InfraRed Spectrometer
- LN₂ cooled photovoltaic InSb detector
- AC operation of LED's at $f = 104\text{kHz}$, 50% duty cycle
 \Rightarrow no RT blackbody background



- polarized EL with $I_{\text{peak}} = 60\text{mA}$ immersed in LHe ($j_{\text{av}} < 20\text{ W/cm}^2$)

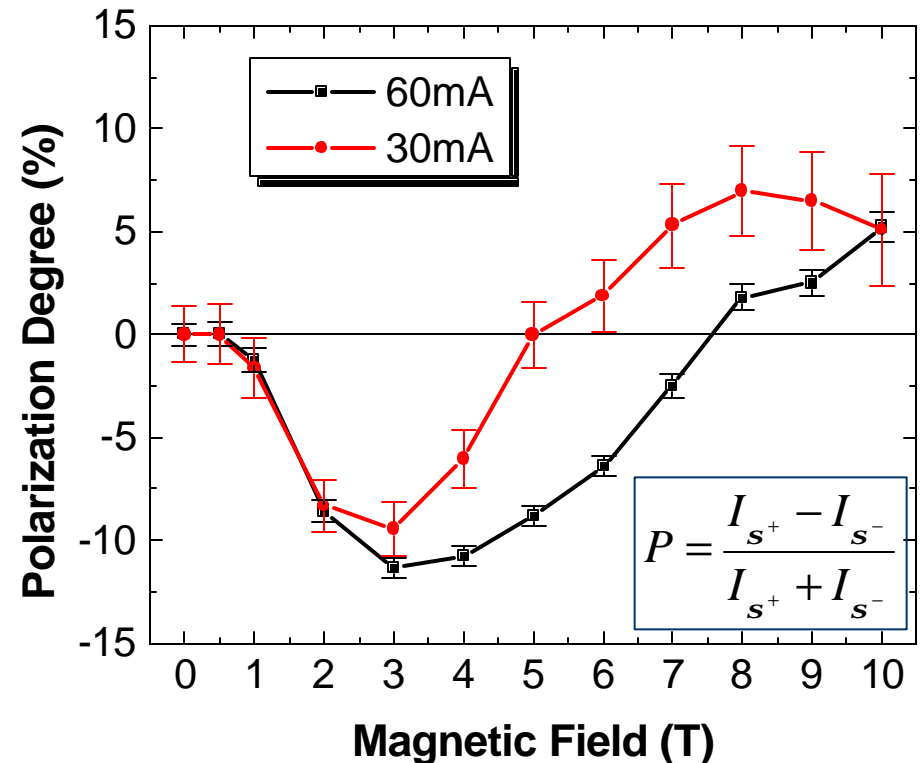
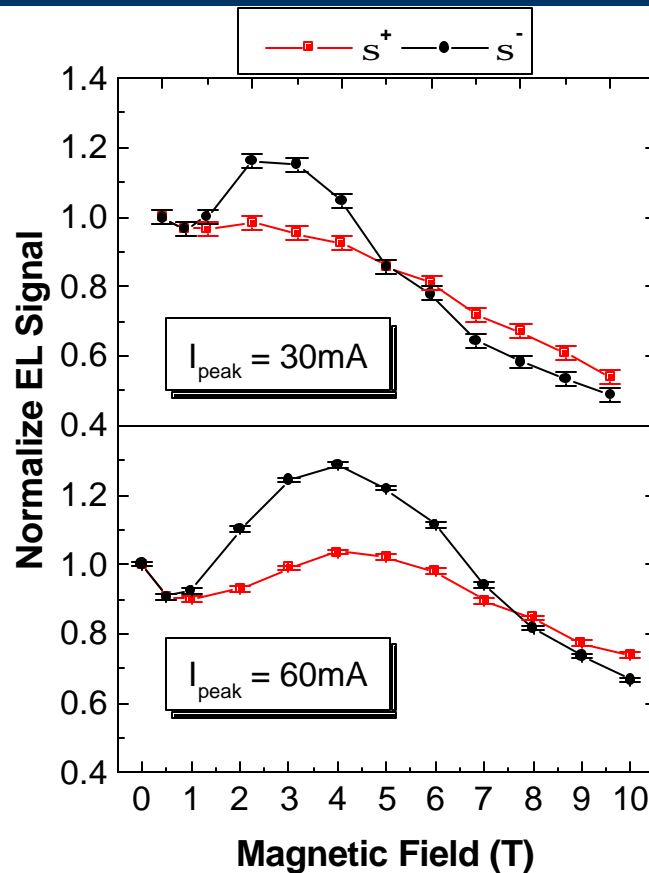
- access opposite polarization by reversal of magnetic field



black lines: s^-
 red lines: s^+

- Low fields: *High energy* σ^- component dominates
- High fields: *Low energy* s^+ component gets stronger and wins

EL intensities and polarization degree

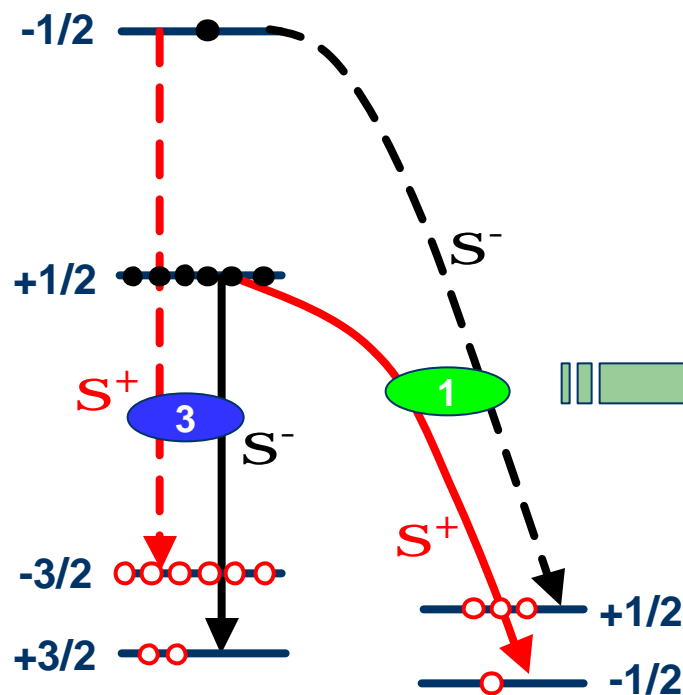


- Measured from peak amplitude of dominant line
- Initial increase with B
- Peak, followed by decrease to ~ 60%
- Different injection currents lead to different values of field at peak

- Polarization degree increases with B
- Peaks at about 3T (about 9 – 12 % depending on injection current)
- Peak followed by sharp decrease and change in sign
- crossover at lower fields for lower current

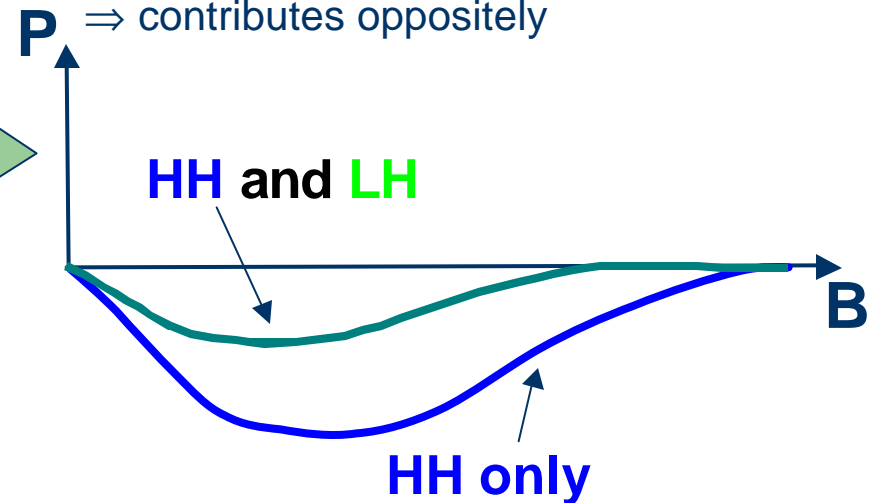
Zeeman splitting in InAs

- 1000Å InAs “well” \Rightarrow bulk InAs
 - $\Rightarrow g_e = -15$
 - $\Rightarrow \Delta E_{hh-lh} < 1\text{meV}$
 - $\Rightarrow |g_h| < |g_e|$
- adopt hole level ordering from J.R. Meyer and I. Vurgaftman @ NRL



Steady State (single carrier T):

- $P = 0$ at $B = 0$ (negligible zero field splitting)
- HH contribution $>$ LH contribution
 - \Rightarrow transition matrix elements HH:LH = 3:1
- HH σ^- transition strongest low T and low B
- $P \rightarrow 0$ as $B \rightarrow \infty$, since transitions between ground state conduction and valence band levels are forbidden and excited states are depopulated
- Including LH will decrease and shift minimum
 - $P \Rightarrow$ contributes oppositely

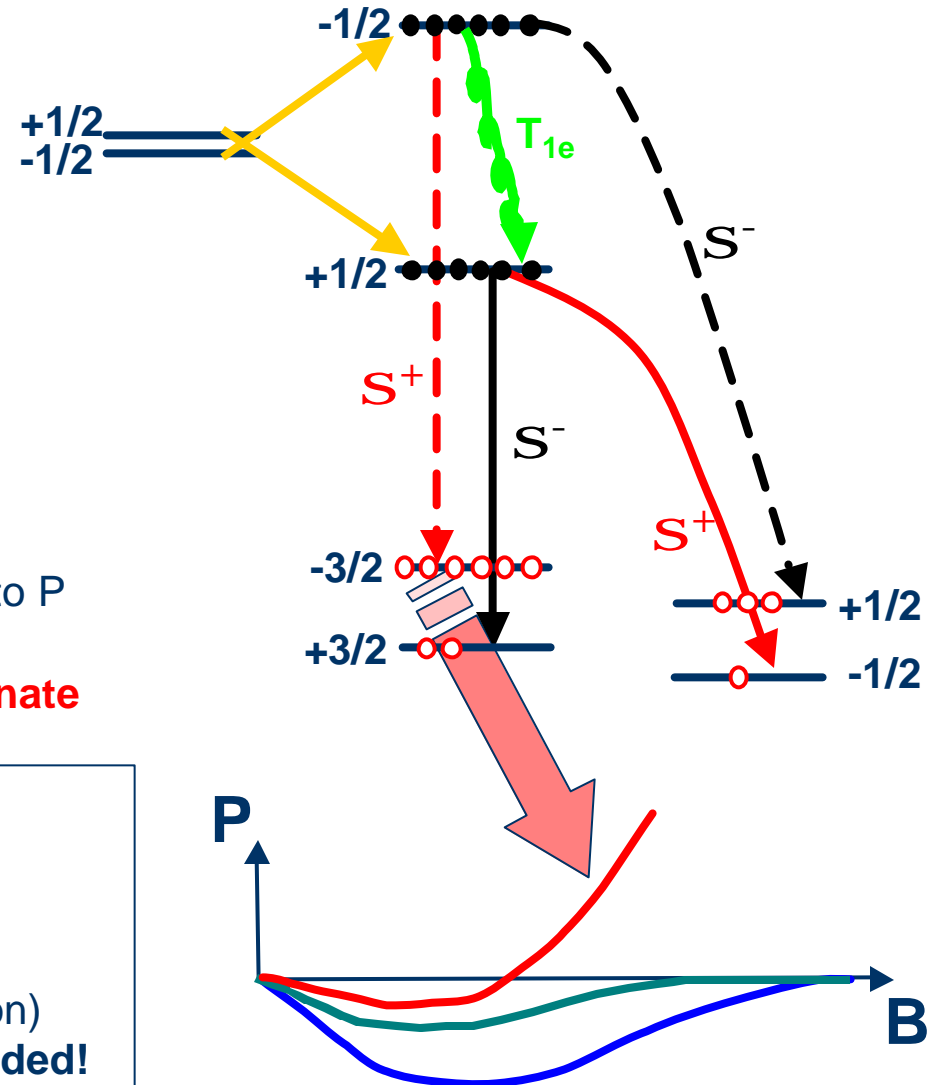


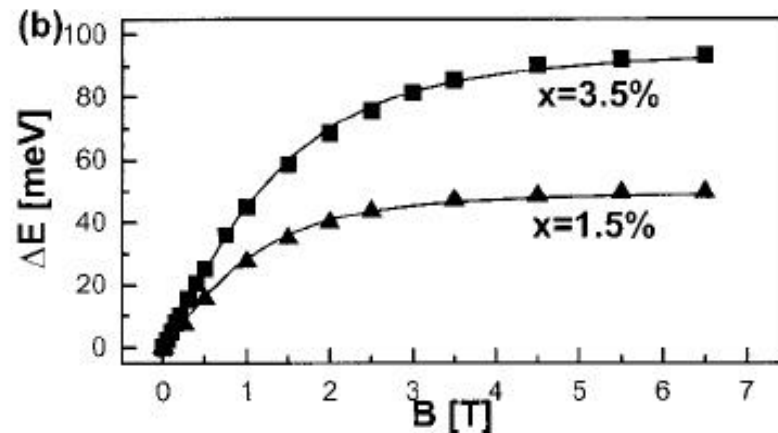
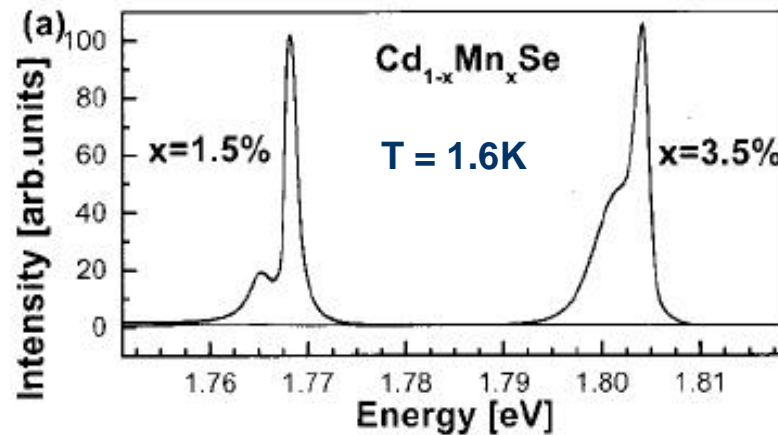
Injection from CdSe

- cubic CdSe $g_e = + 0.46$ negligible (Karimov et al. PRB **62**, 2000)
 \Rightarrow equal injection into $+1/2$ and $-1/2$ states of InAs
- holes are unpolarized and quickly thermalize ($T_{1h} \ll \tau_R$)
- Polarization degree will depend on spin relaxation time T_{1e} :

1. $T_{1e} \ll \tau_R$
 \Rightarrow system thermalizes, no change to P
2. $T_{1e} \gg \tau_R$
 \Rightarrow **s^+ transition will start to dominate**

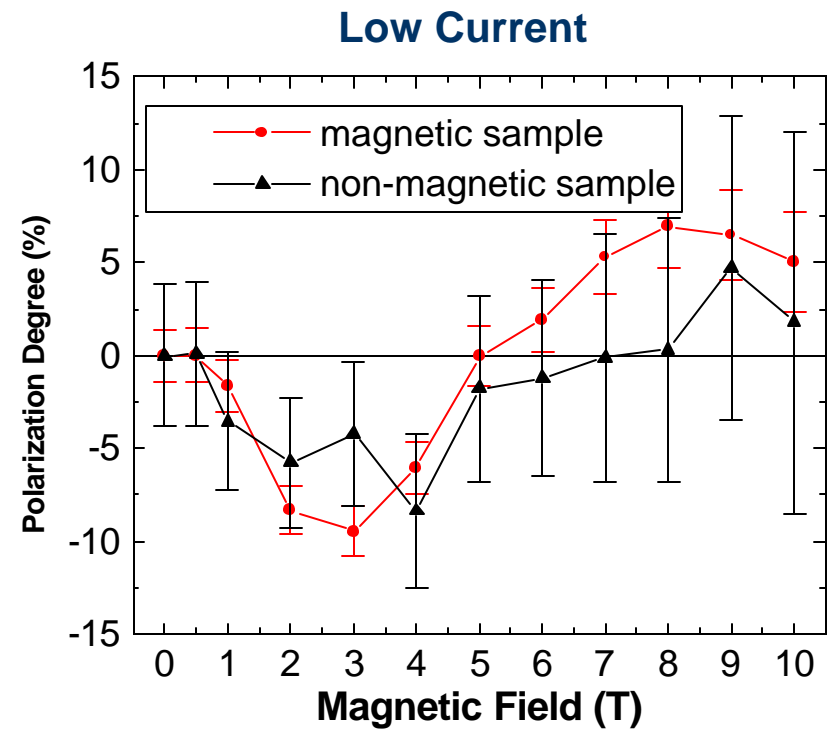
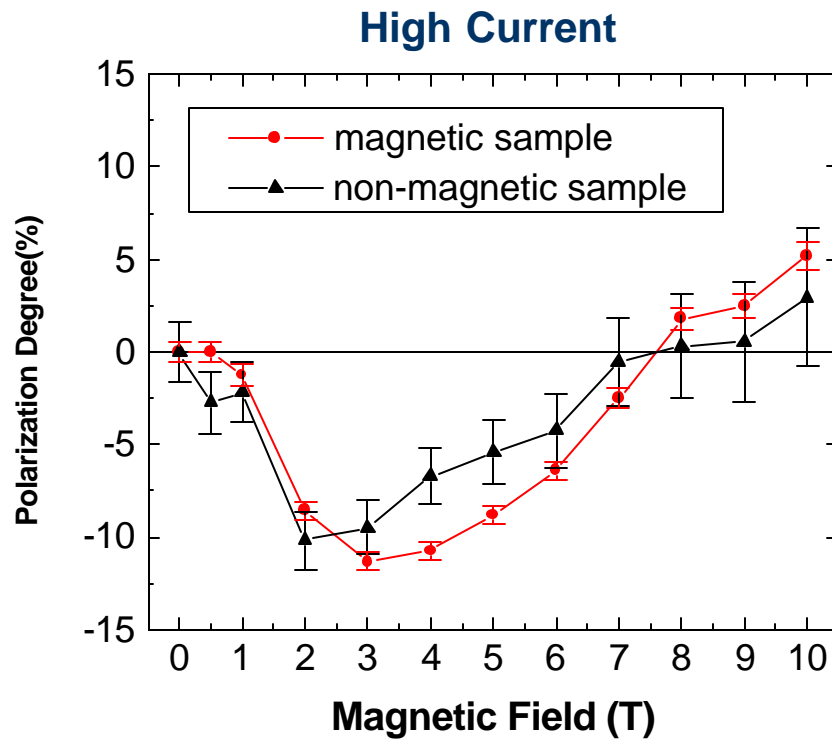
Bulk InAs @ low temperatures:
 $T_{1e} \sim 1 - 10$ ns (Song and Kim, PRB **66**, 2002)
 $\tau_R \sim 1 - 10$ ns (J.R. Meyer, private communication)
P Detailed quantitative analysis needed!



P. Grabs et al., APL **80**, 2002

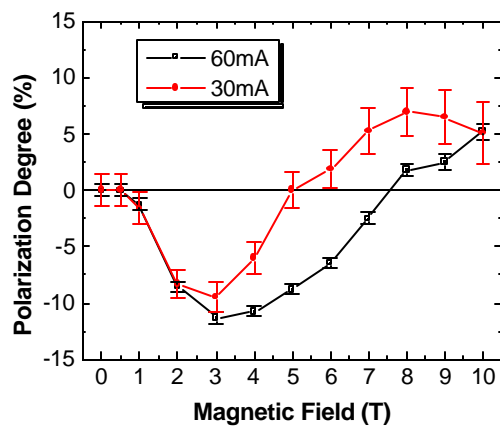
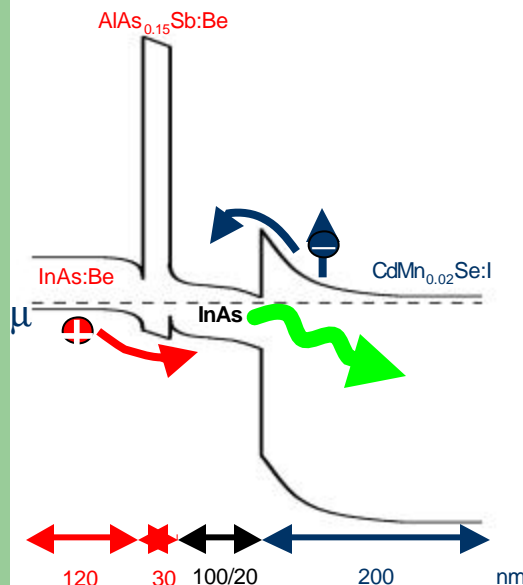
- Paramagnetic DMS CdMnSe: $g_e > 0$
 \Rightarrow exclusive injection into upper $-1/2$ InAs state
 \Rightarrow spin splitting decreases with increasing temperature
- Polarization degree should change sign faster than for non-magnetic CdSe injector
- Crossover field will depend on:
 - **spin-lattice relaxation time T_{1e}**
 - **recombination life time t_R**
 - g_e in InAs
 - g_{hh} and g_{lh} in InAs
 - carrier density in n-type InAs

Magnetic and Non-Magnetic Sample



- Overall signal lower for non-magnetic \Rightarrow significant increase in errors
- Similar qualitative behavior of magnetic and non-magnetic sample
- *Low current*: difference in polarization degree masked by noise
- *High current*: small difference in polarization degree only at intermediate fields

Summary/Plans

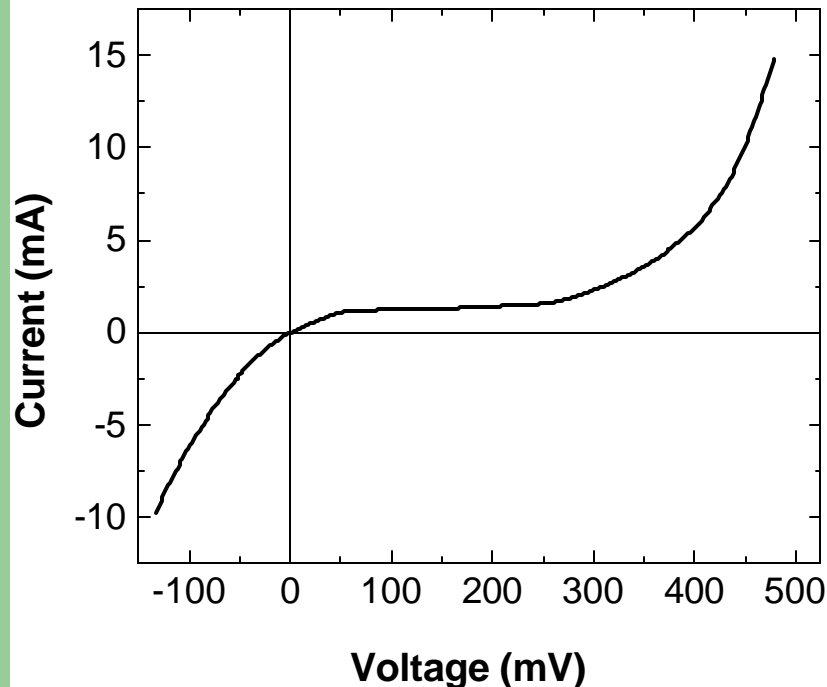


Thanks to J.R. Meyer and I. Vurgaftman

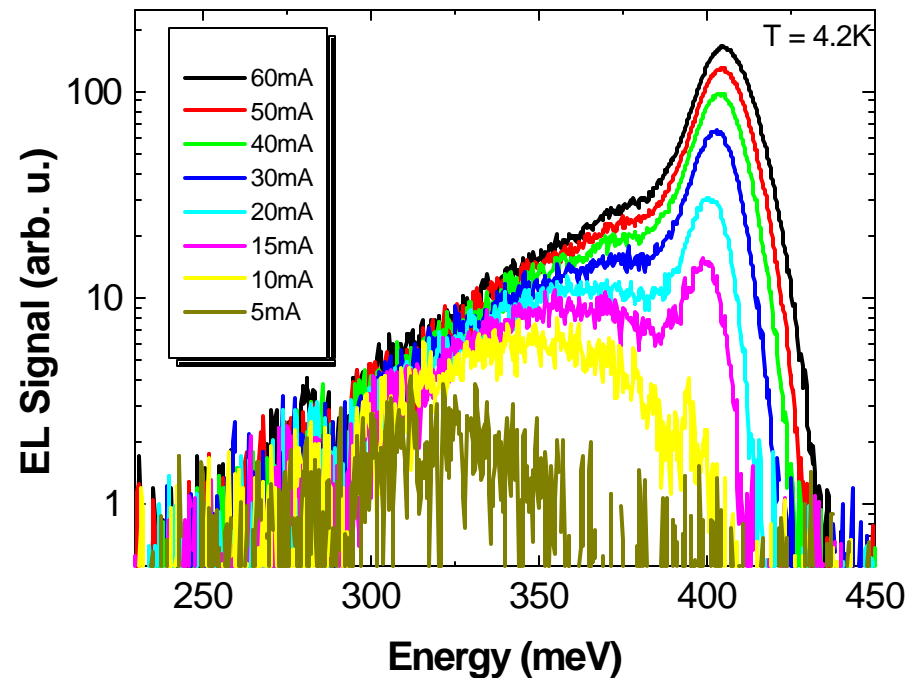
- Circularly polarized EL in MIR from AlAsSb/InAs/CdMnSe Spin-LED's and non-magnetic reference sample
- Difference in P masked by noise but may show some evidence of spin injection at high magnetic fields
- Comparable spin-lattice relaxation time and recombination time render spin-injection difficult
 - ⇒ Large intensity for σ^- and σ^+ at 10T
 - ⇒ Crossover from σ^- and σ^+ at high B
- Possible carrier heating due to high injection currents
- Detailed knowledge of bandstructure including band bending effects and modeling (rate equation) needed for quantitative interpretation
- Sample improvement
 - ⇒ minimize barriers for electrons and holes
 - ⇒ narrower InAs wells (minimize LH competition, reduce τ_R)

IV and EL of magnetic sample

DC – IV @ 4.2K

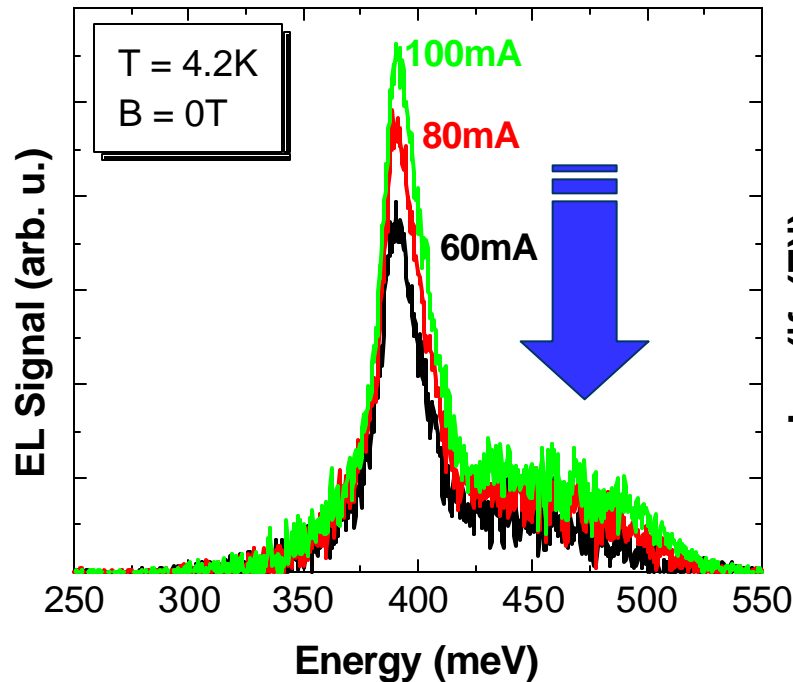


EL in forward bias for different peak currents

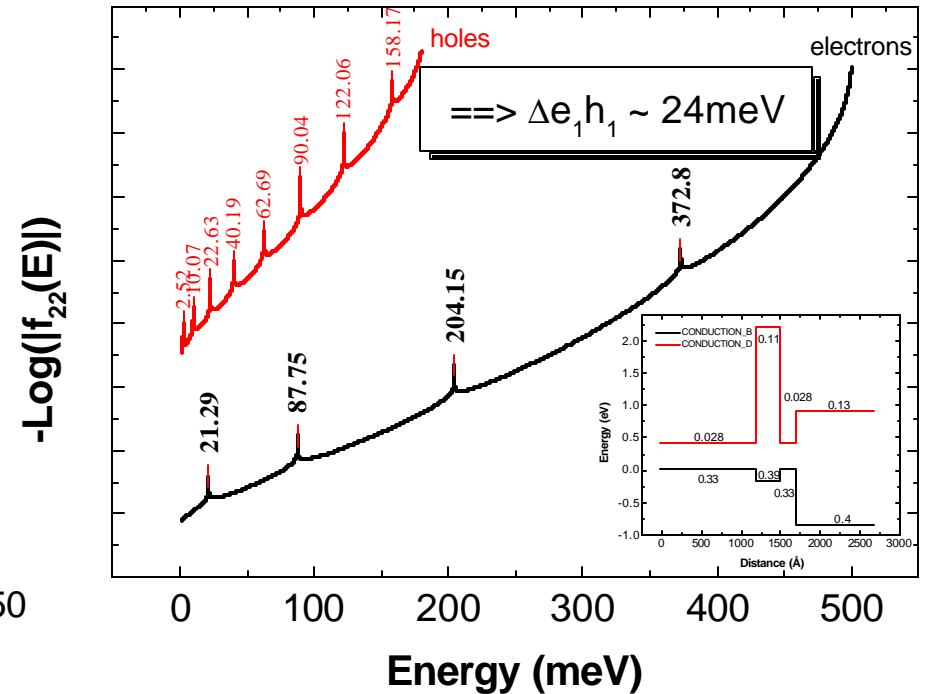


- IV's dominated by tunneling, no clear diode behavior observed
- EL shows two features ("sharp" line near InAs gap; broad band below gap)
- IV and EL data for non-magnetic samples very similar
- some contacts show negative differential resistance

200Å InAs well



- EL of 200Å InAs well
- additional feature above 417 meV due to confinement in well



- Transfer-matrix calculation
 $\Rightarrow e_1 h_1 \sim 24\text{meV}$
- LT- E_{gap} (InAs) = 417meV